

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/635,516	MILNE ET AL.	
Examiner	Art Unit	
Sheela C. Chawan	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
382	124, 116,	11/20/2006	scc		
"	126, 127	11/20/2006	,		
n	312,125	11/20/2006	**		
720	718	11/20/2006	**		
713	186	11/20/2006	91		
42	70.11	11/20/2006	•		
235	380,382	11/20/2006	**		
н	487,492	11/20/2006	**		
365	201, 203	11/20/2006	**		
n	222,228	11/20/2006	<b>11</b>		
n	205,190	11/20/2006	**		
n	189.09	11/20/2006	н		
382	116, 124	7/31/08	SCC		
ABOVE	SEARCH UI	P-DATE ".	SCC		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Éxaminer		
382	116,124	7/31/08	SCC		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST US-PGPUB, USPAT,EPO,JPO,DERWENT, IBM- TDB.	11/20/2006	scc		
INVENTOR NAME SEARCH	11/20/2006	99		
Send y date	5/1407 5/1407	ح در		
SEARCH EAST AND OTHER DATES SEE THE SEARCH REPORT PRI		scc		
382/116,124,126,127,312, 125.CCLS. US-PATENT TEXT SEARCH.	7/31/08	scc		
INTERFERENCE SEARCH	7/31/08	SCC		
SEARCH IEEE OR INSPECT DATABASE.	7/31/08	scc		
ABOVE SEARCH UP-DATE	7/31/08	SCC		